

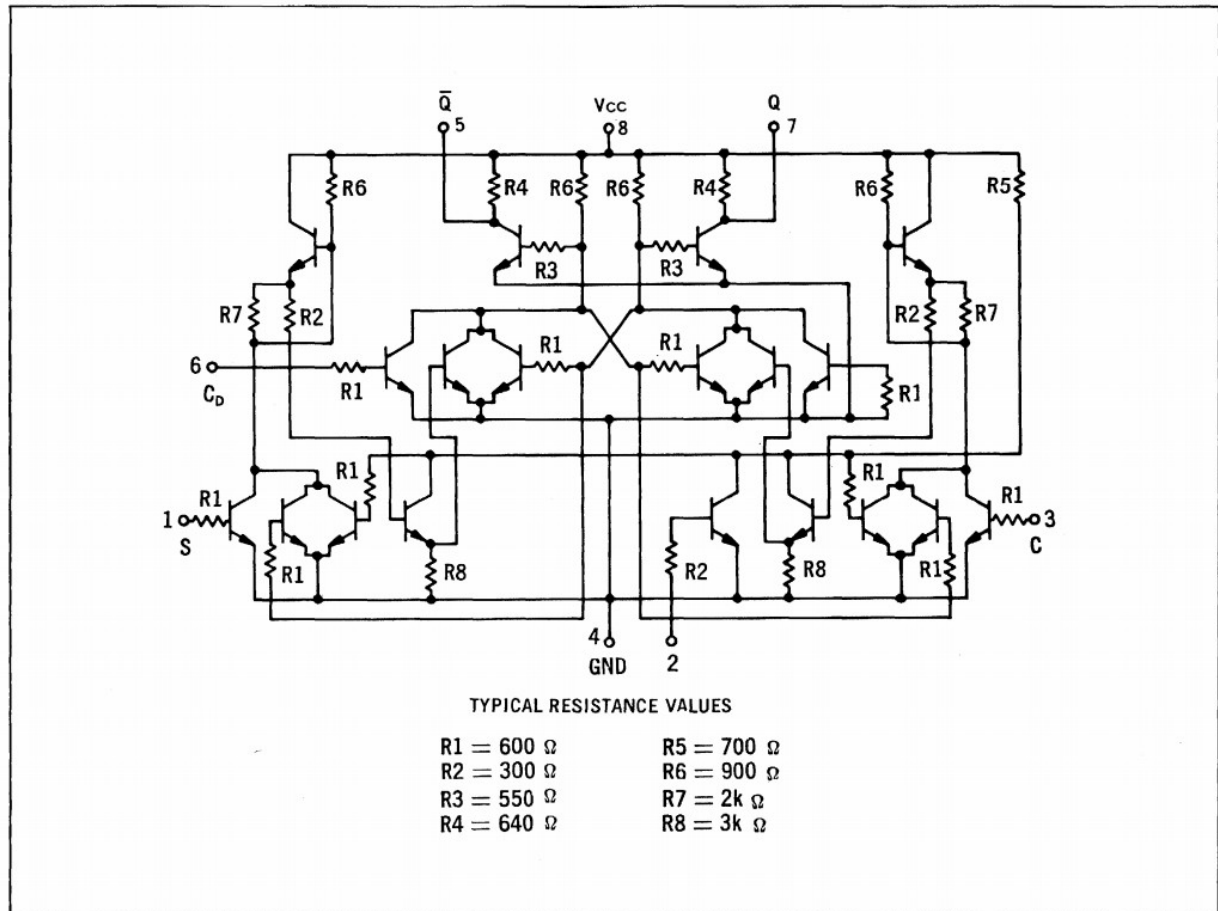
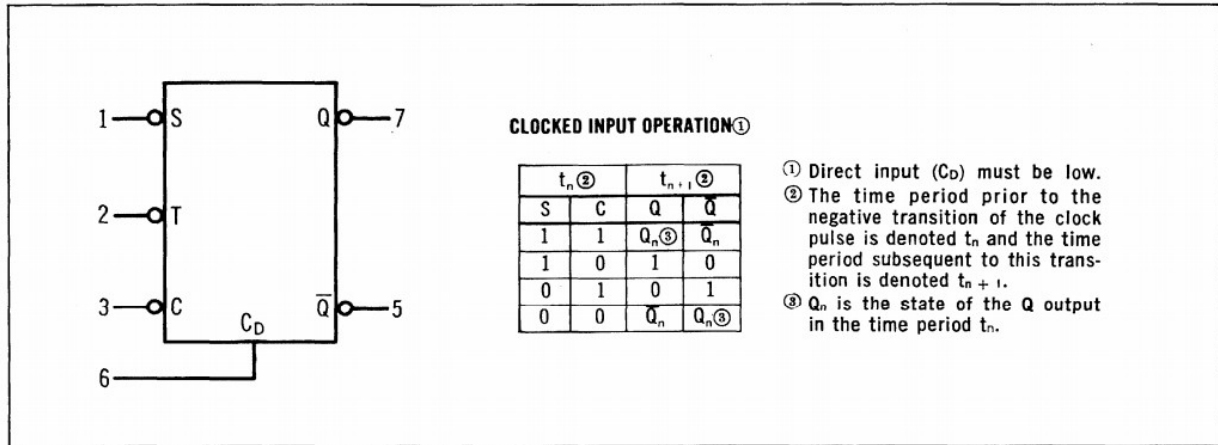
J-K FLIP-FLOPS

MRTL MC900/800 series

MC974 • MC874

Available in TO-99 metal can, add "G" suffix.

J-K flip-flop with a direct clear input in addition to the clocked inputs.



ELECTRICAL CHARACTERISTICS

Characteristic	Symbol	Pin Under Test	TEST VOLTAGE VALUES (Volts)												
			@Test Temperature						TEST VOLTAGE APPLIED TO PINS LISTED BELOW:						
			-55°C		+25°C		+125°C		V _{in}	V _{on}	V _{BOT}	V _{off}	V _{CC}	Gnd	
Input Current	I _{in}	1	-	495	-	435	-	470	μA _{dc}	1	-	6	-	8	4
	2 I _{in} *	2	-	990	-	870	-	940	μA _{dc}	2	-	1,3	-	8	4
	I _{in}	3 Δ	-	495	-	435	-	470	μA _{dc}	3	-	-	-	8	4
	I _{in}	6	-	495	-	435	-	470	μA _{dc}	6	-	-	-	8	4
Output Current	I _{A5}	5 7 Δ	2.47 2.47	-	2.54 2.54	-	2.35 2.35	-	mAdc mAdc	-	5,6 7	-	-	8 8	4 4
	V _{CE(sat)}	5†§ 5†§ 5Δ§ 7Δ 7†§ 7Δ§ 7Δ§	-	200	-	210	-	280	mVdc	-	1	-	3 1,3	8	4

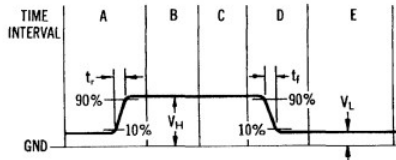
Pins not listed are left open.

Δ Preset the flip-flop by the following procedure:
 (1) Momentarily apply V_{BOT} to pin 6 to preclear flip-flop.
 (2) After V_{BOT} is removed from pin 6, ground pins 1 and 3.
 (3) Apply a negative-going clock pulse to pin 2 (see note §) while pins 1 and 3 are still grounded. This changes the state of the flip-flop to the SET condition.
 (4) Remove the grounds from pins 1 and 3, and proceed with the test.

† Momentarily apply V_{BOT} to pin 6 prior to the arrival of the negative-going clock pulse to effect a change of state.
 § Clock Pulse to pin 2.

MC974, MC874 (continued)

FIGURE 1 — CLOCK PULSE DEFINITION

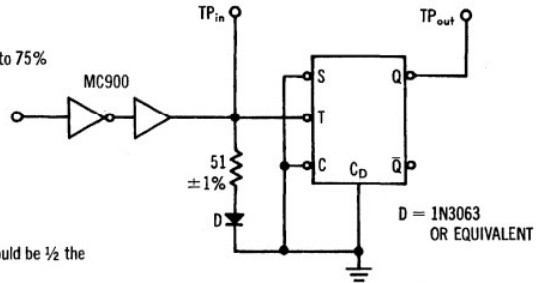


SEQUENCE OF EVENTS:

- A. Voltage applied to Clock pin is raised to V_H . t_r is not critical, however should be less than $1.0 \mu s$.
- B. Biases of all other inputs are applied. V_{CC} is applied without interruption throughout the testing.
- C. Apply momentary ground (when applicable).
- D. Clock pulse is allowed to fall to V_L . t_f must remain within 10 ns minimum and 100 ns maximum.
- E. Electrical measurements are read out. Load current overshoot must be limited to 10% or the flip-flop may be tripped and the wrong output conditions occur.

FIGURE 2 — TOGGLE MODE TEST CIRCUIT

$f = 8 \text{ MHz}$
 DUTY CYCLE = 25% to 75%
 $t_r \text{ \& } t_f \leq 10 \text{ ns}$
 1.0 V
 0



Frequency at TP_{out} should be $\frac{1}{2}$ the frequency at TP_{in} .

D = 1N3063 OR EQUIVALENT

MC874		
T_A	V_L	V_H
25°C	0.554 V	0.894 V
0°C	0.574 V	0.959 V
100°C	0.370 V	0.760 V

MC974		
T_A	V_L	V_H
25°C	0.565 V	0.865 V
-55°C	0.710 V	1.064 V
125°C	0.320 V	0.724 V

All voltages $\pm 10 \text{ mV}$

SWITCHING TIME TEST CIRCUITS AND WAVEFORMS

FIGURE 3A — CLOCK-TO-OUTPUT PROPAGATION DELAY TIME

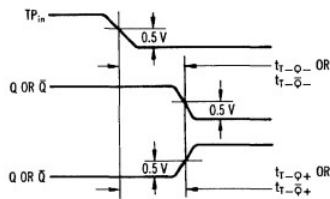
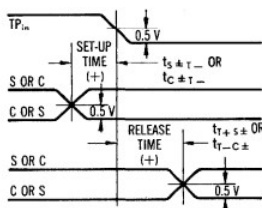


FIGURE 3B — SET-UP AND RELEASE TIME



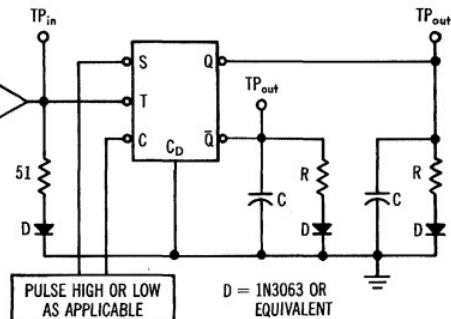
For definitions of set-up and release times, see General Information Section.

FIGURE 3C — TEST CIRCUIT

$f = 1.0 \text{ MHz}$
 $1.0 \text{ ns} < \text{PW} < 200 \text{ ns}$
 DUTY CYCLE = 50%

CIRCUIT LOAD	C^*	R
Heavy	100 pF	90 Ω
Light	15 pF	450 Ω

*Includes jig and probe capacitance



PULSE HIGH OR LOW AS APPLICABLE

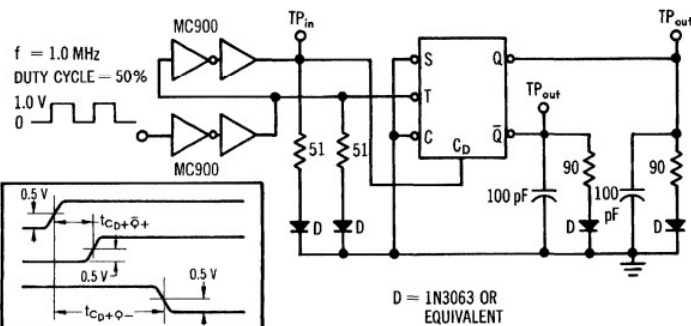
D = 1N3063 OR EQUIVALENT

SWITCHING TIMES

Test	Figure No.	Minimum	Maximum
		Over Full Temperature Range (ns)	
t_{r-o-}	3A, 3C	25#	90
t_{r-o-}	3A, 3C	25#	90
t_{r-o+}	3A, 3C	25#	90
t_{r-o+}	3A, 3C	25#	90
t_{s+}	3B, 3C	—	50
t_{s-}	3B, 3C	—	30
t_{c+}	3B, 3C	—	50
t_{c-}	3B, 3C	—	30
t_{r-s+}	3B, 3C	—	0*
t_{r-s-}	3B, 3C	—	+5*
t_{r-c+}	3B, 3C	—	0*
t_{r-c-}	3B, 3C	—	+5*
t_{cD+}	4	—	90
t_{cD+}	4	—	70

Lightly loaded * Negative switching time means the inputs can momentarily change before the clock pulse transition.

FIGURE 4 — DIRECT CLEAR PROPAGATION DELAY TIME



D = 1N3063 OR EQUIVALENT